


<b>Search Notes</b>  	<b>Application/Control No.</b>  10781461	<b>Applicant(s)/Patent Under Reexamination</b>  WEI ET AL.
	<b>Examiner</b>  BETSY L DEPPE	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Updated class/subclass search of 7/30/07	4/16/08	B. Deppe
Text search (USPAT; US-PGPUB; EPO; JPO; DERWENT' IBM-TDB)	4/16/08	B. Deppe
Inventor name search	4/16/08	B. Deppe
Text search (USPAT; US-PGPUB)	4/17/08	B. Deppe

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	147, 316, 340	4/17/08	B. Deppe
370	320, 335, 342, 441, 479	4/17/08	B. Deppe
455	561	4/17/08	B. Deppe